

# $\overset{\mathsf{October}\,\mathsf{2012}}{\mathbf{SupreMOS}}^{\mathsf{TM}}$

## FCH76N60N

# N-Channel MOSFET 600V, 76A, $36m\Omega$

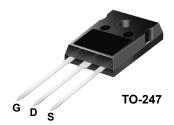
#### **Features**

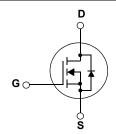
- 650V @TJ = 150°C
- $R_{DS(on)} = 28m\Omega$  (Typ.)@  $V_{GS} = 10V$ ,  $I_D = 38A$
- Ultra Low Gate Charge (Typ.Q<sub>g</sub> = 218nC)
- · Low Effective Output Capacitance
- 100% Avalanche Tested
- · RoHS Compliant

## **Description**

The SupreMOS MOSFET, Fairchild's next generation of high voltage super-junction MOSFETs, employs a deep trench filling process that differentiates it from preceding multi-epi based technologies. By utilizing this advanced technology and precise process control, SupreMOS provides world class Rsp, superior switching performance and ruggedness.

This SupreMOS MOSFET fits the industry's AC-DC SMPS requirements for PFC, server/telecom power, FPD TV power, ATX power, and industrial power applications.





## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol		Parameter		Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage			600	V
$V_{GSS}$	Gate to Source Voltage	Gate to Source Voltage			V
	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		76	^
ID	Drain Current	-Continuous (T <sub>C</sub> = 100°C)		48.1	Α
I <sub>DM</sub>	Drain Current	- Pulsed (N	Note 1)	228	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)			8022	mJ
I <sub>AR</sub>	Avalanche Current			25.3	Α
E <sub>AR</sub>	Repetitive Avalanche Energy			5.43	mJ
al/al#	MOSFET dv/dt Ruggedness	MOSFET dv/dt Ruggedness			\//
dv/dt	Peak Diode Recovery dv/dt	1)	Note 3)	20	V/ns
Б	Davies Dissination	$(T_C = 25^{\circ}C)$		543	W
$P_D$	Power Dissipation	- Derate above 25°C		4.34	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

## **Thermal Characteristics**

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.23	
$R_{\theta CS}$	Thermal Resistance, Case to Heat Sink (Typical)	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient 4		

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCH76N60N	FCH76N60N	TO-247	-	-	30

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$ , $V_{GS} = 0V$ , $T_C = 25^{\circ}C$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.73	-	V/°C
1	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 480V, V <sub>GS</sub> = 0V	-	-	10	
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 480V, V_{GS} = 0V, T_{C} = 125^{\circ}C$	-	-	100	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

### **On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 38A$	-	28	36	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20V, I_{D} = 38A$	-	90	ı	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 400V V 0V	-	9310	12385	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V — f = 1MHz	-	370	495	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	-	3.1	5	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380V, V_{GS} = 0V, f = 1MHz$	-	195	-	pF
C <sub>oss</sub> eff.	Effective Output Capacitance	$V_{DS}$ = 0V to 380V, $V_{GS}$ = 0V	-	914	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	218	285	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 380V, I_{D} = 38A,$	-	39	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V (Note 4)	-	66	-	nC
ESR	Equivalent Series Resistance(G-S)	Drain Open	-	1	-	Ω

## **Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time			-	34	78	ns
t <sub>r</sub>	Turn-On Rise Time	V <sub>DD</sub> = 380V, I <sub>D</sub> = 38A		-	24	58	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{GEN} = 25\Omega$		-	235	480	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4)	-	32	74	ns

## **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	76	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	228	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 38A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 38A	-	612	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	16	-	μС

#### Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2.  $I_{AS}$  = 25.3A,  $R_{G}$  = 25 $\Omega$ , Starting  $T_{J}$  = 25 $^{\circ}$ C
- 3. I\_{SD}  $\leq$  76A, di/dt  $\leq$  200A/µs, V\_DD  $\leq$  380V, Starting T\_J = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

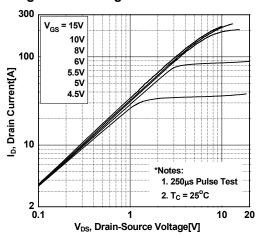


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

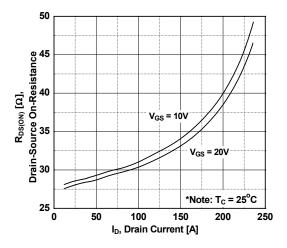


Figure 5. Capacitance Characteristics

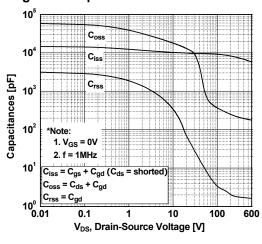


Figure 2. Transfer Characteristics

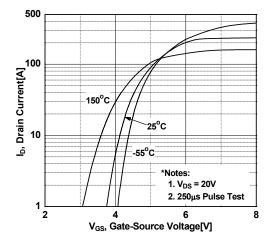


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

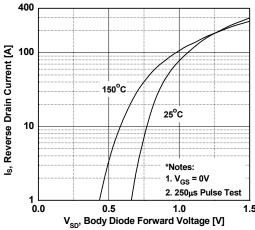
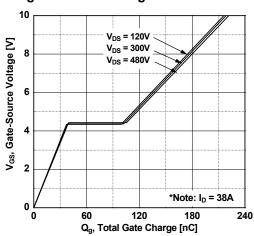


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

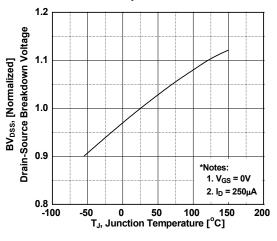


Figure 8. On-Resistance Variation vs. Temperature

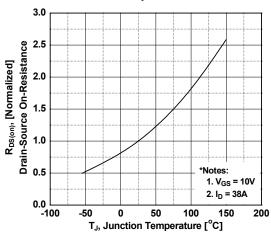


Figure 9. Maximum Safe Operating Area

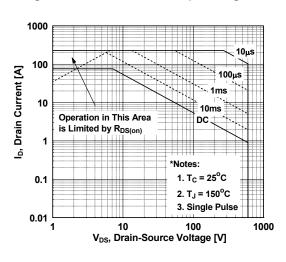


Figure 10. Maximum Drain Current vs. Case Temperature

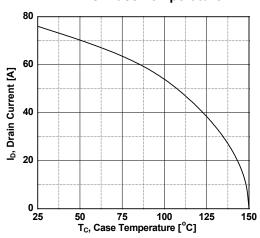
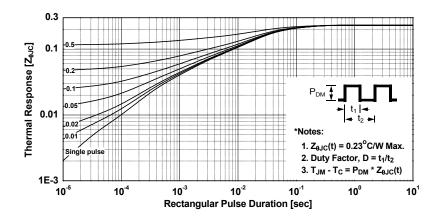
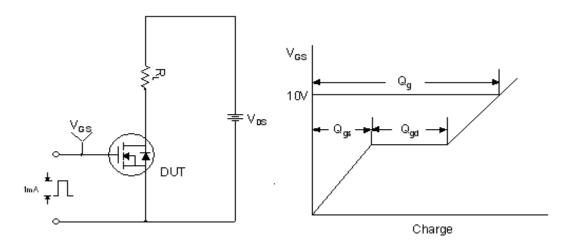


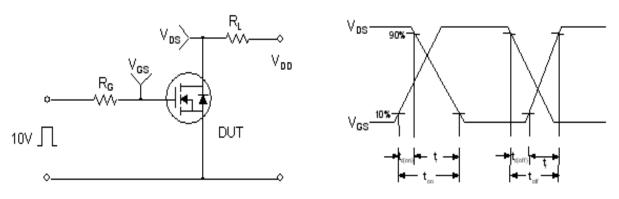
Figure 11. Transient Thermal Response Curve



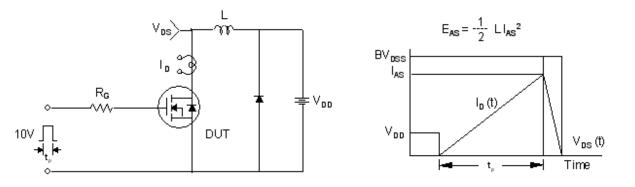
## **Gate Charge Test Circuit & Waveform**



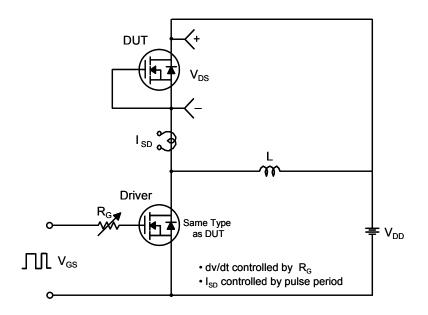
## **Resistive Switching Test Circuit & Waveforms**

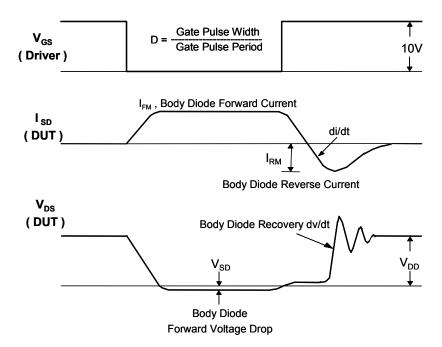


## **Unclamped Inductive Switching Test Circuit & Waveforms**



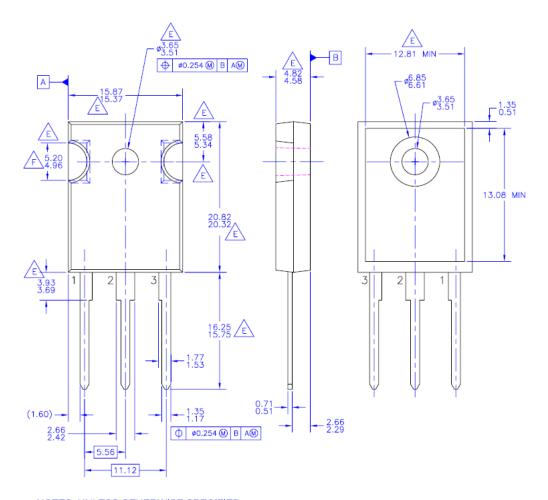
### Peak Diode Recovery dv/dt Test Circuit & Waveforms





## **Mechanical Dimensions**

# TO-247



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